








List of Facilities for Microstructure Characterization, BARC to Share with UGC-DAE-CSR (Mumbai)

S. No	Instrument	Research Area	Contact Person	Phone No. (Extn)	Photograph, if you intend to include
1.	<p>Scanning Electron Microscope (FIB-FESEM) Make: Carl Zeiss Model: Auriga FESEM Gun: Field emission (FESEM), Ion beam (FIB) Voltage: up to 30 KV Detectors: SE, In lens, BSE, EBSD, Oxford EDS</p>	Microstructure Characterization	<p>Head, MSD rtewari@barc.gov.in B. Viswanadh bvisu@barc.gov.in</p>	022-25595065/ 022-25592022	
2.	<p>Transmission Electron Microscope Make: Carl Zeiss Model: Libra200FE Voltage: up to 200 KV Gun: Field emission Modes Of Operation: Bright Field, Dark Field, High resolution imaging, HAADF Composition analysis: Bruker EDS, EELS</p>	High resolution microstructure Characterization	<p>Head, MSD / Dr. S. Neogy rtewari@barc.gov.in and neosuman@barc.gov.in</p>	022-25595065 and 022-25595465	

3.	<p>Electron Probe Micro Analyser Make: CAMECA Model: SX100 Voltage: up to 30 KV Gun: Tungsten Filament Modes Of Operation: SE, BSE, X-ray Composition analysis: Bruker EDS, WDS</p>	Chemical analysis and quantification at micron level	Head, MSD / Dr. Pranesh Sengupta rtewari@barc.gov.in and sengupta@barc.gov.in	022-25595065 and 022-25590468	
4.	<p>Electron Spectroscopy for Chemical Analysis (ESCA) with Auger Electron Spectroscopy (AES) system Make: Specs GambH Model: HXPS Voltage: 1.5 kV Gun: Low energy electron gun (upto 10 eV), Mg/Al X-ray anodes Modes of Operation: Surface analysis and depth profiling Composition analysis: detectable upto 0.1at%; from C- to U in ESCA and Li to F in AES</p>	Characterization of electronic state at the Surface of sample	Head, MSD / Dr. Pranesh Sengupta rtewari@barc.gov.in and sengupta@barc.gov.in	022-25595065 and 022-25590468	

5.	<p>Transmission Electron Microscope Make: JEOL Model: JEOL3010 Voltage: up to 300 KV Gun: LaB6 Modes Of Operation: Bright Field, Dark Field, High resolution imaging, Precession electron Diffraction Composition analysis: Oxford EDS</p>	<p>Microstructure and micro texture Characterization</p>	<p>Head, MSD rtewari@barc.gov.in B. Viswanadh bvisu@barc.gov.in</p>	<p>022-25595065/ 022-25592022</p>	
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6.	3D APT	Atomic level chemical composition	Dr. A. Biswas abiswas@barc.gov.in	022-25593815	
7.	Knudsen Cell Set up	Thermodynamic property measurements as a function of temperature	Dr. U. Jain uttamj@barc.gov.in	022-25592908	

8.	3D profilometer	Surface characterization	Dr. Kulwant Singh singhkw@barc.gov.in	022-25595378	
9.	100 kN Universal Testing Machine Sample: Round – M6, M8, M12, Flat 1-8 mm Strain rate - 1×10^{-4} to 1×10^{-2} 1/s Temperature – 25-900 °C	Mechanical Testing - Tensile, Compression,	Head, MMD / Dr. B. C. Maji rnsingh@barc.gov.in and bikchan@barc.gov.in	022-25593817 022-25592932	

10.	<p>Creep Testing Machine Sample: Round –M8, M12, Flat 1-6 mm Temperature – 25-900 °C</p>	Creep	Head, MMD / Dr. A. Sarkar rnsingh@barc.gov.in and asarkar@barc.gov.in	022-25593817	
11.	<p>Differential Scanning Calorimeter Make: Mettler Toledo Temperature range: RT - 600°C; Heating rates: 1K/min to 50K/min; Cooling rates: not controllable; Sample dimensions: Thin metallic samples of size ~ 5 mm and approx. weight 50-100 mg Environment : Nitrogen / Argon gas</p>	Phase transformation	Head, MMD / Dr. J. B. Singh rnsingh@barc.gov.in and jbsingh@barc.gov.in	022-25592358	
12.	<p>100 kN Universal Testing Machine Sample: Round – M6, M8, M12, Flat 1-8 mm Strain rate - 1×10^{-4} to 1×10^{-2} 1/s Temperature – 25-900 °C</p>	Mechanical Testing - Tensile, Compression,	Head, MMD / Dr. B. C. Maji rnsingh@barc.gov.in and bikchan@barc.gov.in	022-25593817 022-25592932	